

<b>Notice of References Cited</b>	Application/Control No. 10/750,368	Applicant(s)/Patent Under Reexamination LUCK ET AL.	
	Examiner Binh V. Ho	Art Unit 2163	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,941,316	09-2005	Venkatesh et al.	707/101
*	B	US-2005/0203950	09-2005	Rajan et al.	707/103.00R
*	C	US-2004/0267766	12-2004	Marek et al.	707/100
*	D	US-6,968,503	11-2005	Chang et al.	715/526
*	E	US-2003/0191769	10-2003	Crisan et al.	707/100
*	F	US-2005/0050054	03-2005	Clark et al.	707/100
*	G	US-2005/0091183	04-2005	Cunningham et al.	707/001
*	H	US-5,644,768	07-1997	Periwal et al.	718/102
*	I	US-2005/0055354	03-2005	Thompson et al.	707/100
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.